

Notice of References Cited	Application/Control No. 10/086,025	Applicant(s)/Patent Under Reexamination ANDERSON ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 1 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,892,458	04-1999	Anderer et al.	340/10.41
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Maxwell, S. L., III et al, Nuclear Materials Management 1990, 19, 199-202. ✓			
	V	Dohi, K. et al, R&D, Research and Development (Kobe Steel Ltd.) 1991, 41, 146-147. ✓			
	W	Agudo, M. et al, Analytica Chimica Acta 1992, 264, 265-273. ✓			
	X	Park, C. J. et al, Analytical Science & Technology 1995, 8, 427-434. ✓			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/086,025	Applicant(s)/Patent Under Reexamination ANDERSON ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 2 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Waygood, J. B., Proceedings of the Chemists' Conference 1995, 47th, 64-68. /
	V	Ketterer, M. E. et al, Analytical Chemistry 1996, 68, 883-887. /
	W	Jinghong, H. et al, Sensors and Actuators B 1996, 35-36, 422-426. /
	X	Stewart, I. I. et al, Journal of Analytical Atomic Spectrometry 1996, 11, 1203-1214. /

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/086,025	Applicant(s)/Patent Under Reexamination ANDERSON ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 3 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Olesik, J. W. et al, Journal of Analytical Atomic Spectrometry 1997, 12, 507-515. ✓			
	V	Zoorob, G. et al, Journal of Analytical Atomic Spectrometry 1997, 12, 517-524. ✓			
	W	Baron, D. et al, Journal of Environmental Quality 1998, 27, 844-850. ✓			
	X	Raffaelli, A. et al, Inorganica Chimica Acta 1998, 275-276, 462-469. ✓			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/086,025	Applicant(s)/Patent Under Reexamination ANDERSON ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 4 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	May, T. W. et al, Atomic Spectroscopy 1998, 19, 143-149. ✓
	V	Ross, A. R. S. et al, Analytical Chemistry 1998, 70, 2225-2235. ✓
	W	Schramel, O. et al, ournal of Chromatography, A 1998, 819, 231-242. ✓
	X	Godec, R. et al, Semiconductor Pure Water and Chemicals Conference 1999, 18th, 91-110. ✓

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/086,025	Applicant(s)/Patent Under Reexamination ANDERSON ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 5 of 5

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Szpunar, J. et al, Chemia Analityczna (Warsaw) 1999, 44, 351-362. ✓
	V	Henderson, W. et al, Inorganica Chimica Acta 1999, 294, 183-192. ✓
	W	Mollah, S. et al, Analytical Chemistry 2000, 72, 985-991. ✓
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.